

 UTM UNIVERSITI TEKNOLOGI MALAYSIA	PUSAT PENGURUSAN MAKMAL UNIVERSITI (PPMU)	Form Num.	UIRL/F/124
		Version	1/2023
		Effective Date	01/02/2023
		Equipment	XPS
		Sample Serial No.	
X-RAY & THERMAL ANALYSIS LABORATORY			
SAMPLE SUBMISSION FORM (INDUSTRY)			

General Rules and Requirements:

1. All information provided should be true
2. Booking will be notified/updated by email
3. Booking procedure
 - a. Submit the complete application form to UIRL Sample Acceptance Counter
 - b. **Fast Lane is offered to non-UTM customers with an additional 50% charge from the normal price**
4. Sample Condition & Preparation
 - a. **PPMU has the right to cancel any analysis if the sample is suspected to have a high risk on the safety of the operator or can cause damage to the instrument during the analysis. The cost of damages will be borne by the customer.**
 - b. The sample's weight for powder samples must not be less than 200mg.
 - c. The sample's size for solid samples is not more than 1 cm X 1 cm.
 - d. **The remaining samples will be disposed of within a month after analysis is completed.**
5. All inquiries regarding XPS should be forwarded to to the (Science Officer, Mrs. Amy Zuria binti Abdul Ajid, email: amyzuria@utm.my or Assistant Engineer, Muhamad Arif bin Misset: m.arifmisset@utm.my, tel: 07-5557725), or visit our website at ppmu.utm.my.

1. APPLICANT'S PERSONAL PARTICULARS								
Name of Applicant								
Hand Phone No.								
Email								
Signature & Official Stamp		<i>*A digital signature is not recommended. Any matters raised in the future are beyond our responsibilities.</i>						
2. COMPANY DETAILS								
Name								
Registration No.								
Address								
Hand Phone No.								
Email								
Mode of payment		Cash	<input type="checkbox"/>	EFT	<input type="checkbox"/>	Invoice	<input type="checkbox"/>	Fast Lane
3. SAMPLE INFORMATION								
Name of Sample								
Number of Sample								
Sample Labels								
Type of Sample		Powder	<input type="checkbox"/>	Solid	<input type="checkbox"/>			
Composition / impurities								
Special Sample Handling Instruction								
Brief Description of the Analysis Goals (use back side if needed)								
High Resolution Scan (Elements: Ex: C 1s, Cu 2p, O 1s, Si 2p)								
Note: XPS is a surface sensitive technique; please do not touch the area(s) of analysis when handling the sample								